

**Notice of References Cited**

Application/Control No.

10/552,562

Applicant(s)/Patent Under  
Reexamination  
ANTONCIC ET AL.

Examiner

SUN JAE Y. LOEWE

Art Unit

1626

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0149279	08-2003	Kumar et al.	548/530
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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